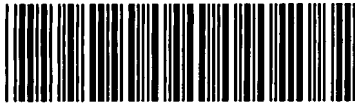


Search Notes

Application/Control No.

10/526,223

Examiner

Louis K. Huynh

Applicant(s)/Patent under
Reexamination

TANAKA ET AL.

Art Unit

3721

SEARCHED

Class	Subclass	Date	Examiner
53	403 472 139.5	5/18/2007	/LH/
206	521 522	5/18/2007	/LH/
383	3	5/18/2007	/LH/

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR